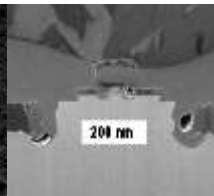




**NanoScope Services Ltd.**

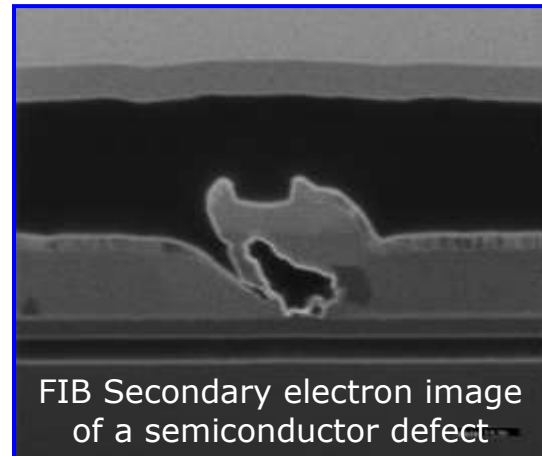


## **NanoMEGAS TEM section preparation package**

*Get 5 TEM sections made from your samples using FIB – ideal for orientation imaging and strain solutions at 1-5 nm resolution using ASTAR/Digistar/Topspin/Autostrain.*

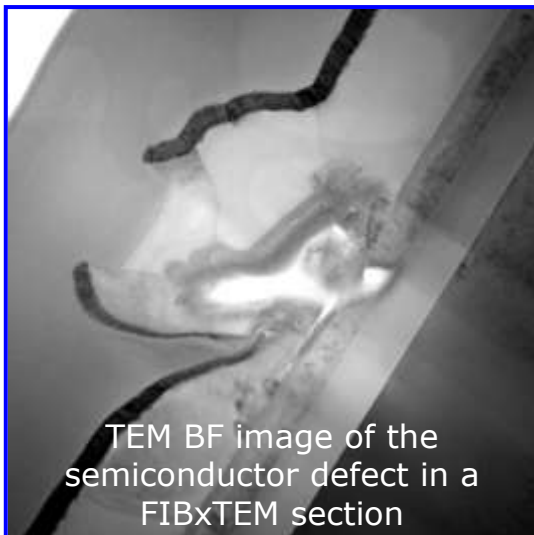
TEM sections can be machined from the top surface of your samples at exact locations and orientations using our Focused Ion Beam section preparation service (via NanoScope Services UK).

The sections are typically 15-18 microns long, 8-10 microns deep and <100nms thick. They are extracted from the sample and transferred to a copper TEM grid with a support film and are then immediately available for TEM imaging, grain orientation and strain analysis in the TEM with **NanoMEGAS** solutions installed.



FIB Secondary electron image of a semiconductor defect

Good sample quality is vital to achieving good images and good analytical results in the TEM. The advanced grain orientation capabilities of the **ASTAR/Digistar/Topspin products** and the strain mapping solutions at nm scale (**Autostrain**), are also dependant of having the best samples from exactly the right locations. FIB technology and section extraction have been used for years by TEM users looking at specific locations, and this package of TEM section preparation is the perfect complement to the **NanoMEGAS** products.



TEM BF image of the semiconductor defect in a FIBxTEM section

NanoScope has been at the forefront of developing these FIB techniques and can now offer exclusively to **NanoMEGAS** customers, this package of TEM section preparations.

### **Package includes**

5 X standard TEM sections (see definitions) prepared by FIB from specified locations and transferred to Cu TEM grid, with a 2-3 weeks turnaround.

**Special prices apply with package included with NanoMEGAS products and solutions**

### **Additional options available**

Faster turnaround, very specific locations, sub-thinned section regions, sputter coated surface protection (C, Au), amorphous layer reduction, wedged section profiles

and written reports. Additional charges for these options apply

For more information about this section preparation package please contact at [info@nanomegas.com](mailto:info@nanomegas.com) or go to <http://www.nanosopeservices.co.uk/materials-scientists-academics-industrial/> and download the support documents.